Search Notes				

Application No.	Applicant(s)	
10/604,895	WU, CHING-HSIU	
Examiner	Art Unit	
Stephen W. Smoot	2813	

SEARCHED Class Subclass Date Examiner 438 4 8/7/2004 SWS 438 14 8/7/2004 SWS 438 623 8/7/2004 SWS 438 763 8/7/2004 SWS 438 780 8/7/2004 SWS 438 782 8/7/2004 SWS 438 788 8/7/2004 SWS Updated Above 12/3/2004 SWS					_
438 4 8/7/2004 SWS 438 14 8/7/2004 SWS 438 623 8/7/2004 SWS 438 763 8/7/2004 SWS 438 780 8/7/2004 SWS 438 782 8/7/2004 SWS 438 788 8/7/2004 SWS	. "	SEAR	CHED		
438 14 8/7/2004 SWS 438 623 8/7/2004 SWS 438 763 8/7/2004 SWS 438 780 8/7/2004 SWS 438 782 8/7/2004 SWS 438 788 8/7/2004 SWS	Class	Subclass	Date	Examiner	
438 623 8/7/2004 SWS 438 763 8/7/2004 SWS 438 780 8/7/2004 SWS 438 782 8/7/2004 SWS 438 788 8/7/2004 SWS	438	4	8/7/2004	sws	
438 763 8/7/2004 SWS 438 780 8/7/2004 SWS 438 782 8/7/2004 SWS 438 788 8/7/2004 SWS	438	14	8/7/2004	sws	
438 763 8/7/2004 SWS 438 780 8/7/2004 SWS 438 782 8/7/2004 SWS 438 788 8/7/2004 SWS	438	623	8/7/2004	sws	\X.W.&,
438 782 8/7/2004 SWS 438 788 8/7/2004 SWS	438	763	8/7/2004	sws](
438 788 8/7/2004 SWS	438	780	8/7/2004	sws]
	438	782	8/7/2004	sws])
Updated Above 12/3/2004 SWS &, ,	438	788	8/7/2004		Y .
	Updated	Above	12/3/2004	sws	W.L.
i i i i i i i i i i					

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	,			
Same a	s Above	12/3/2004	sws	

SEARCH NOT (INCLUDING SEARCH)
(DATE	EXMR
Key Words: Spin-on Material - Glass, SOG, Resist, Photoresist, MSQ, HSQ, Silsesquioxane;	8/7/2004	SWS,
Clean, Wash, Rinse - Scrub; Interconnect - Wiring, Trace, Line, Conductor, Metal, Copper, Aluminum;	8/7/2004	17,2, sws
Etch - Dry, Wet, BHF, Ashing, Stripping.	8/7/2004	S.W.F. sws
Updated Above Search	12/3/2004	S.W.J.
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	8/7/2004 & 12-3+04	sws My.S.
-		